

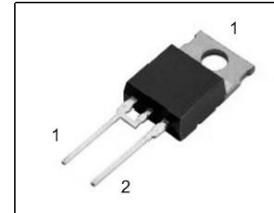
**Silicon Carbide Schottky Diode**

- Worlds first 600V Schottky diode
- Revolutionary semiconductor material - Silicon Carbide
- Switching behavior benchmark
- No reverse recovery
- No temperature influence on the switching behavior
- No forward recovery
- Pb-free lead plating; RoHS compliant
- Qualified according to JEDEC<sup>0)</sup> for target applications

**thinQ!™ SiC Schottky Diode**
**Product Summary**

|           |     |    |
|-----------|-----|----|
| $V_{RRM}$ | 600 | V  |
| $Q_c$     | 30  | nC |
| $I_F$     | 12  | A  |

PG-T0220-2-2.



| Type     | Package       | Ordering Code | Marking | Pin 1 | Pin 2 |
|----------|---------------|---------------|---------|-------|-------|
| SDT12S60 | PG-T0220-2-2. | Q67040-S4470  | D12S60  | C     | A     |

**Maximum Ratings**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

| Parameter   | Symbol            | Value       | Unit                 |
|---|-------------------|-------------|----------------------|
| Continuous forward current, $T_C=100^\circ\text{C}$   | $I_F$             | 12          | A                    |
| RMS forward current, $f=50\text{Hz}$  | $I_{FRMS}$        | 17          |                      |
| Surge non repetitive forward current, sine halfwave<br>$T_C=25^\circ\text{C}$ , $t_p=10\text{ms}$ | $I_{FSM}$         | 36          |                      |
| Repetitive peak forward current<br>$T_j=150^\circ\text{C}$ , $T_C=100^\circ\text{C}$ , $D=0.1$    | $I_{FRM}$         | 49          |                      |
| Non repetitive peak forward current<br>$t_p=10\mu\text{s}$ , $T_C=25^\circ\text{C}$               | $I_{FMAX}$        | 120         |                      |
| $i^2t$ value, $T_C=25^\circ\text{C}$ , $t_p=10\text{ms}$  | $\int i^2 dt$     | 6.48        | $\text{A}^2\text{s}$ |
| Repetitive peak reverse voltage   | $V_{RRM}$         | 600         | V                    |
| Surge peak reverse voltage  | $V_{RSM}$         | 600         |                      |
| Power dissipation, $T_C=25^\circ\text{C}$   | $P_{tot}$         | 88.2        | W                    |
| Operating and storage temperature   | $T_j$ , $T_{stg}$ | -55... +175 | $^\circ\text{C}$     |

<sup>0</sup>J-STD20 and JESD22

**Thermal Characteristics**

| Parameter                                      | Symbol     | Values |      |      | Unit |
|--|------------|--------|------|------|------|
|  |            | min.   | typ. | max. |      |
| <b>Characteristics</b>                         |            |        |      |      |      |
| Thermal resistance, junction - case            | $R_{thJC}$ | -      | -    | 1.7  | K/W  |
| Thermal resistance, junction - ambient, leaded | $R_{thJA}$ | -      | -    | 62   |      |

**Electrical Characteristics**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

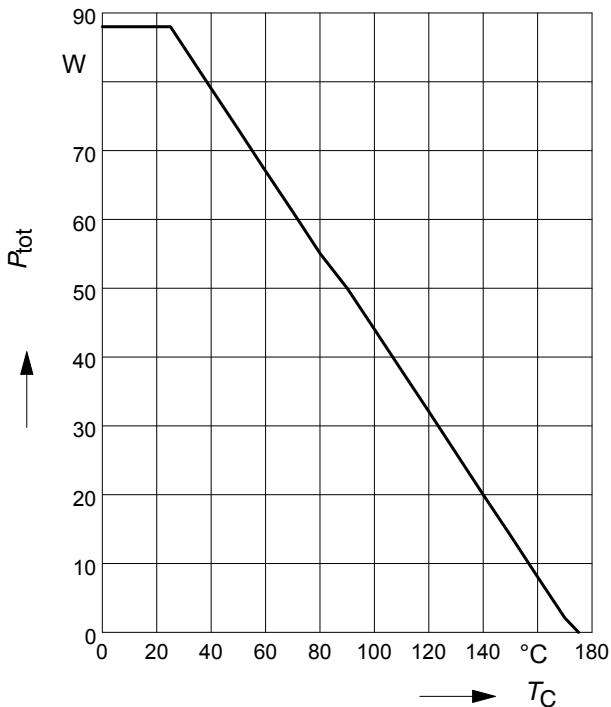
| Parameter   | Symbol | Values |      |      | Unit          |
|---|--------|--------|------|------|---------------|
|   |        | min.   | typ. | max. |               |
| <b>Static Characteristics</b>                                   |        |        |      |      |               |
| Diode forward voltage<br>$I_F=12\text{A}, T_j=25^\circ\text{C}$ | $V_F$  | -      | 1.5  | 1.7  | V             |
| $I_F=12\text{A}, T_j=150^\circ\text{C}$                         |        | -      | 1.7  | 2.1  |               |
| Reverse current<br>$V_R=600\text{V}, T_j=25^\circ\text{C}$      | $I_R$  | -      | 40   | 400  | $\mu\text{A}$ |
| $V_R=600\text{V}, T_j=150^\circ\text{C}$                        |        | -      | 100  | 2000 |               |

**Electrical Characteristics**, at  $T_j = 25^\circ\text{C}$ , unless otherwise specified

| Parameter   | Symbol   | Values |      |      | Unit |
|---|----------|--------|------|------|------|
|   |          | min.   | typ. | max. |      |
| <b>AC Characteristics</b>   |          |        |      |      |      |
| Total capacitive charge<br>$V_R=400\text{V}, I_F=12\text{A}, di_F/dt=200\text{A}/\mu\text{s}, T_j=150^\circ\text{C}$  | $Q_C$    | -      | 30   | -    | nC   |
| Switching time<br>$V_R=400\text{V}, I_F=12\text{A}, di_F/dt=200\text{A}/\mu\text{s}, T_j=150^\circ\text{C}$   | $t_{rr}$ | -      | n.a. | -    | ns   |
| Total capacitance<br>$V_R=1\text{V}, T_C=25^\circ\text{C}, f=1\text{MHz}$<br>$V_R=300\text{V}, T_C=25^\circ\text{C}, f=1\text{MHz}$<br>$V_R=600\text{V}, T_C=25^\circ\text{C}, f=1\text{MHz}$ | $C$      | -      | 450  | -    | pF   |
|   |          | -      | 45   | -    |      |
|   |          | -      | 43   | -    |      |

### 1 Power dissipation

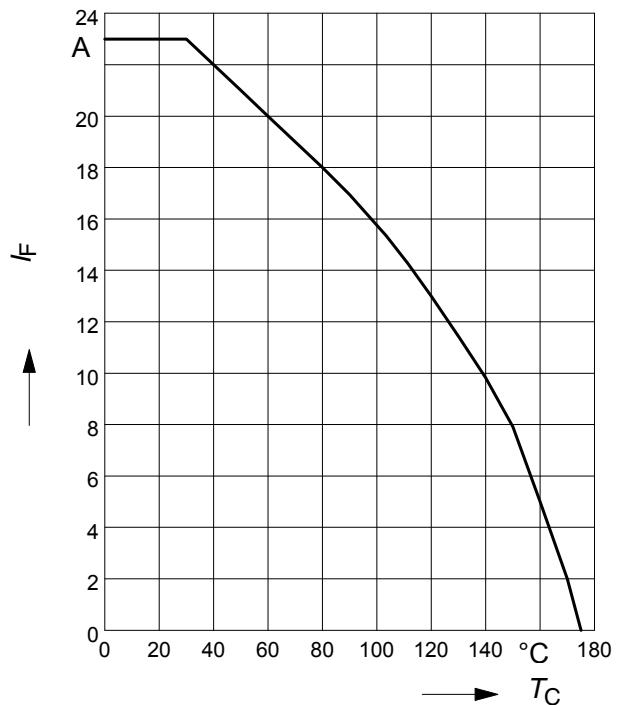
$$P_{\text{tot}} = f(T_C)$$



### 2 Diode forward current

$$I_F = f(T_C)$$

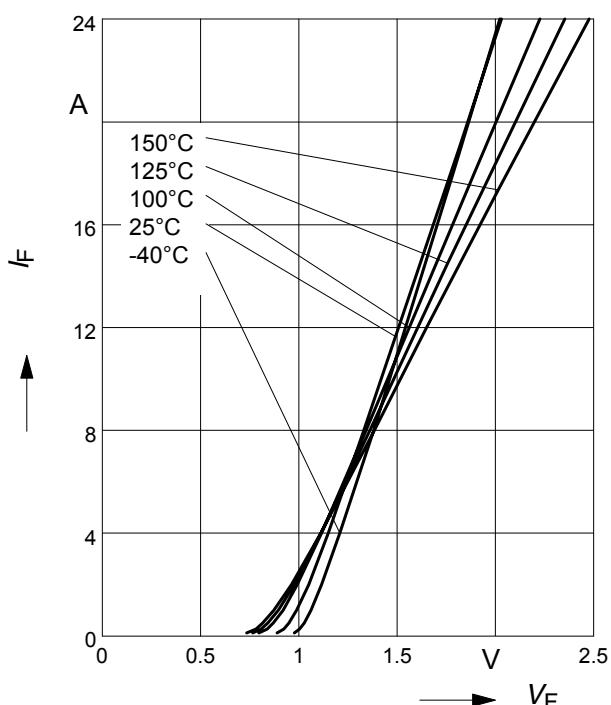
parameter:  $T_j \leq 175^\circ\text{C}$



### 3 Typ. forward characteristic

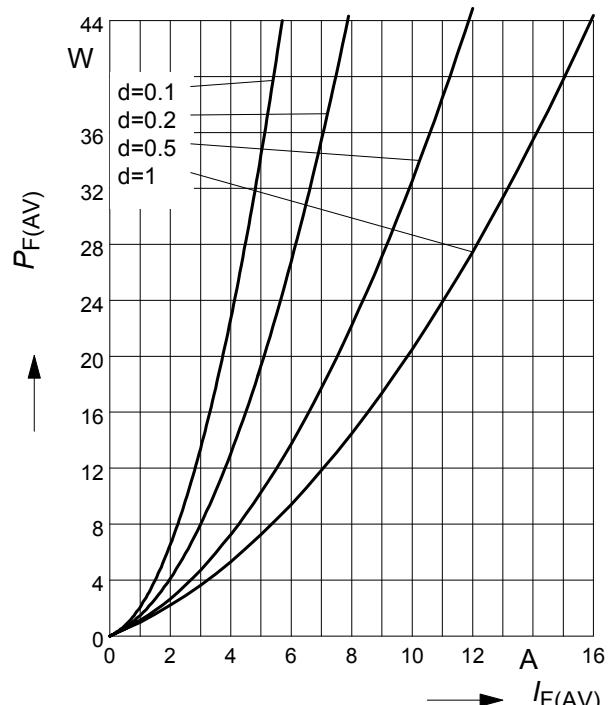
$$I_F = f(V_F)$$

parameter:  $T_j$ ,  $t_p = 350 \mu\text{s}$



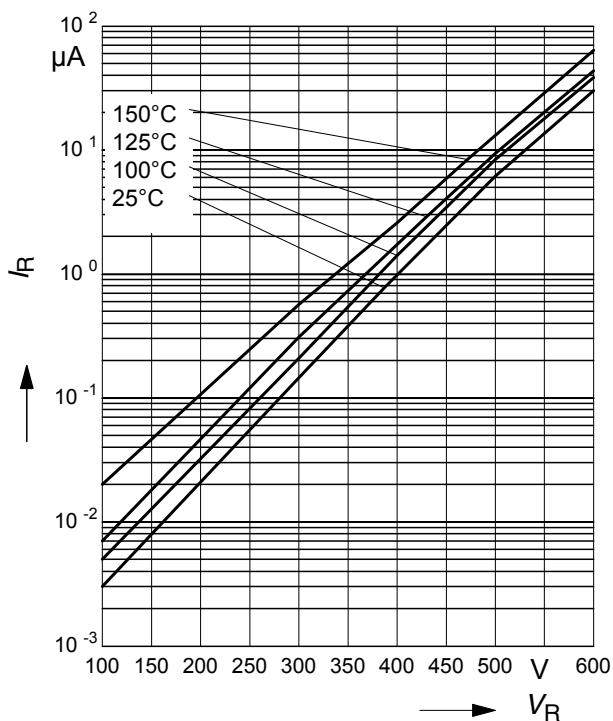
### 4 Typ. forward power dissipation vs. average forward current

$$P_{F(\text{AV})} = f(I_F) \quad T_C = 100^\circ\text{C}, d = t_p/T$$



### 5 Typ. reverse current vs. reverse voltage

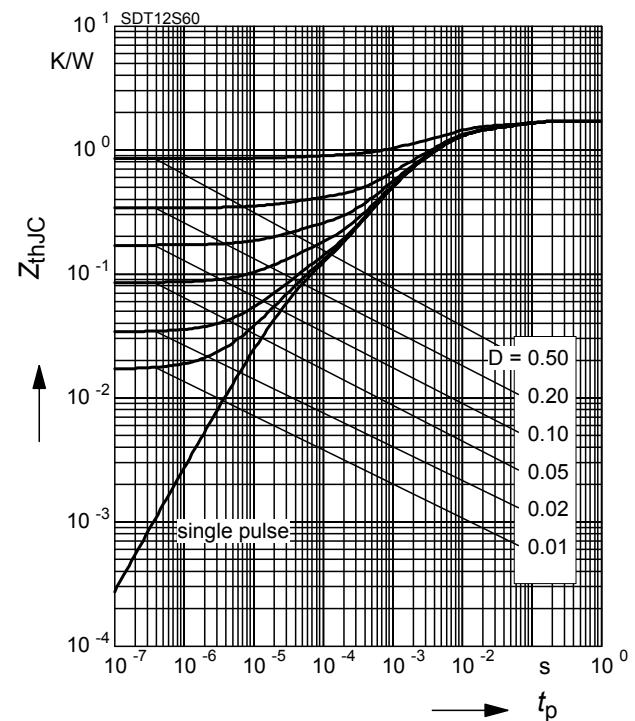
$$I_R = f(V_R)$$



### 6 Transient thermal impedance

$$Z_{\text{thJC}} = f(t_p)$$

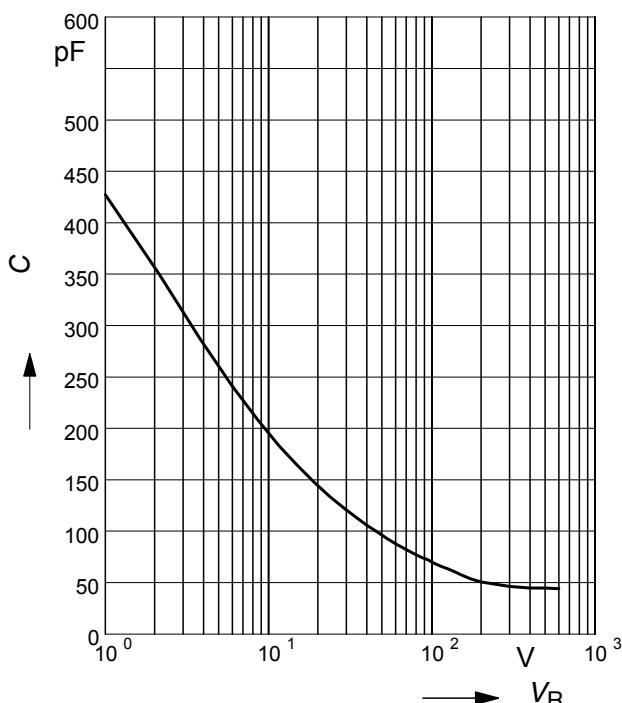
parameter :  $D = t_p/T$



### 7 Typ. capacitance vs. reverse voltage

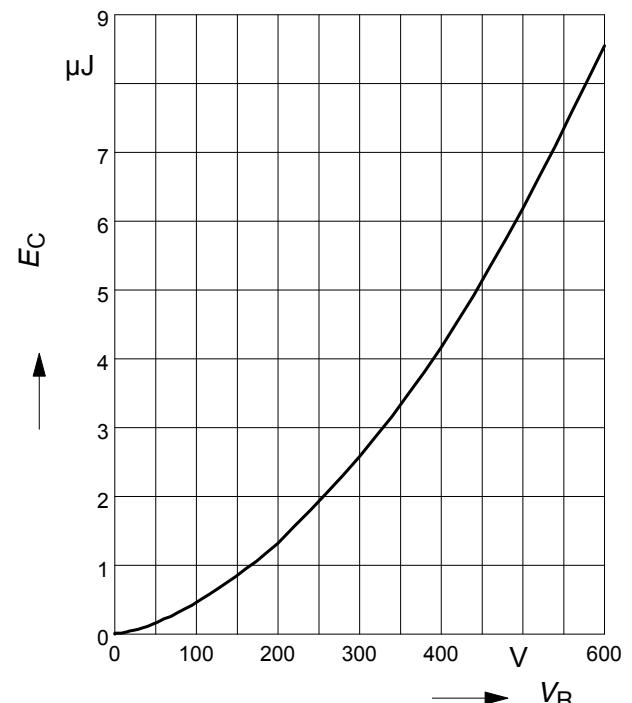
$$C = f(V_R)$$

parameter:  $T_C = 25^\circ\text{C}$ ,  $f = 1 \text{ MHz}$



### 8 Typ. C stored energy

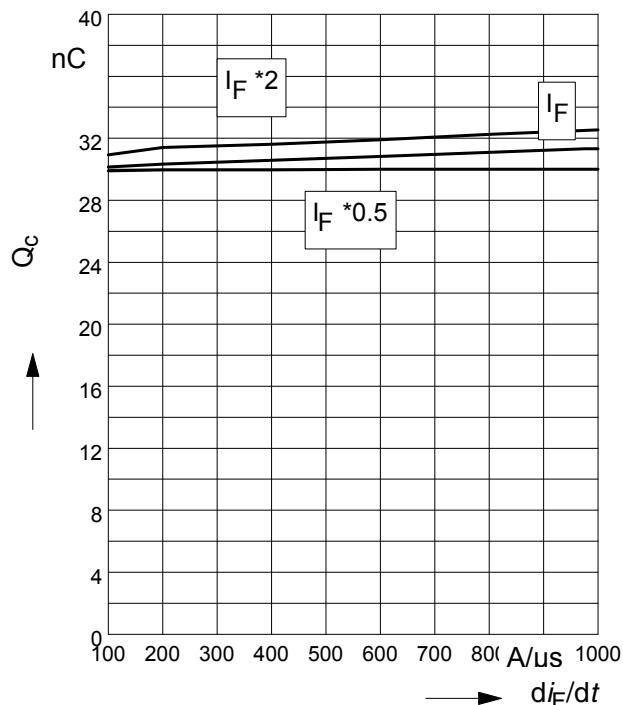
$$E_C = f(V_R)$$

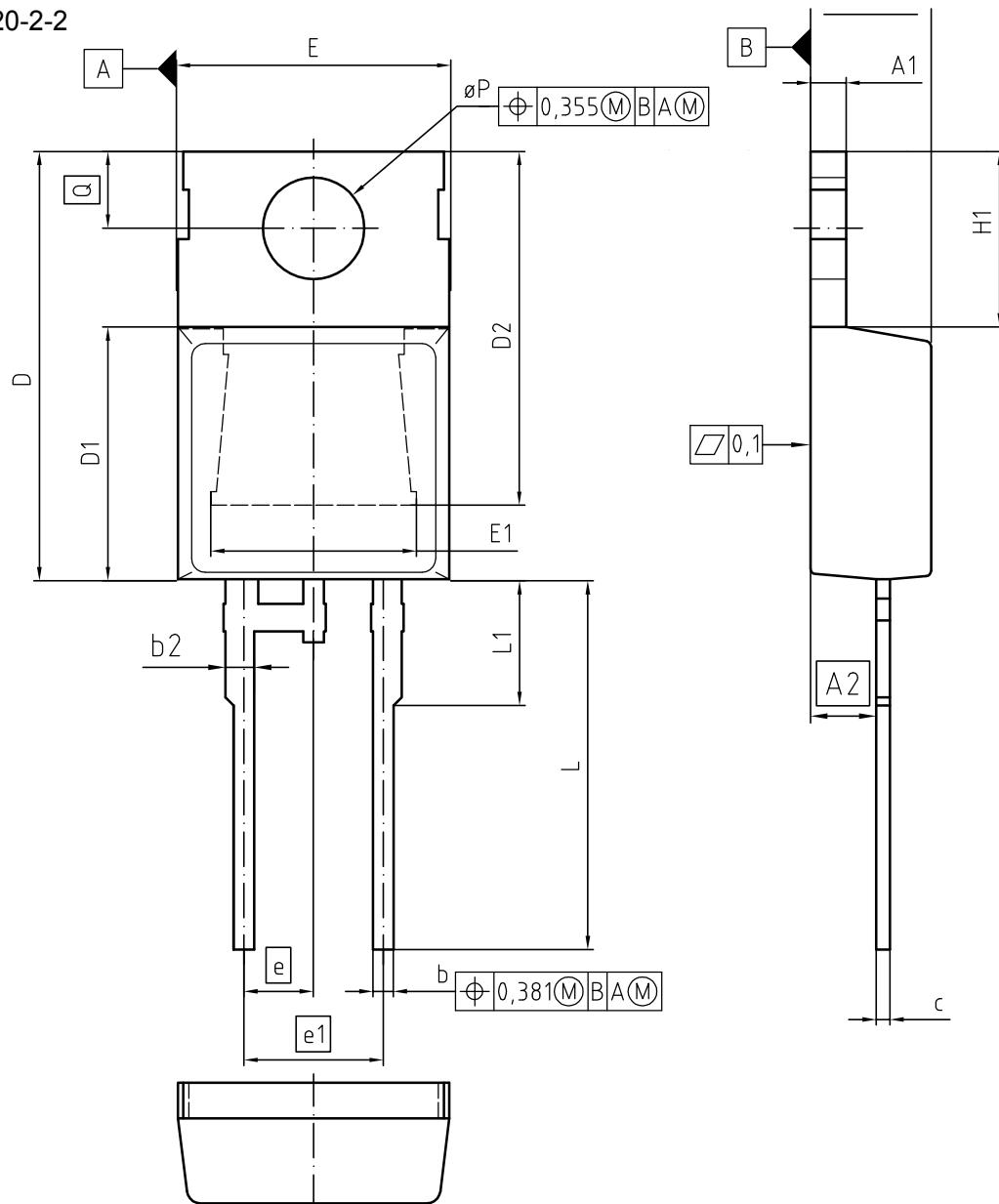


## 9 Typ. capacitive charge vs. current slope

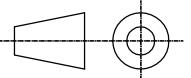
$$Q_C = f(dI_F/dt)$$

parameter:  $T_j = 150 \text{ } ^\circ\text{C}$



**PG-T0-220-2-2**


| DIM | MILLIMETERS |        | INCHES |       |
|-----|-------------|--------|--------|-------|
|     | MIN         | MAX    | MIN    | MAX   |
| A   | 4.191       | 4.699  | 0.165  | 0.185 |
| A1  | 1.170       | 1.400  | 0.046  | 0.055 |
| A2  | 2.215       | 2.718  | 0.087  | 0.107 |
| b   | 0.635       | 0.889  | 0.025  | 0.035 |
| b2  | 0.950       | 1.651  | 0.037  | 0.065 |
| c   | 0.330       | 0.635  | 0.013  | 0.025 |
| D   | 14.808      | 15.950 | 0.583  | 0.628 |
| D1  | 8.509       | 9.450  | 0.335  | 0.372 |
| D2  | 12.850      | 14.245 | 0.506  | 0.561 |
| E   | 9.677       | 10.363 | 0.381  | 0.408 |
| E1  | 6.500       | 8.788  | 0.256  | 0.346 |
| e   | 2.540       |        | 0.100  |       |
| e1  | 5.080       |        | 0.200  |       |
| N   | 2           |        | 2      |       |
| H1  | 5.900       | 6.900  | 0.232  | 0.272 |
| L   | 12.700      | 14.000 | 0.500  | 0.551 |
| L1  | 3.048       | 4.800  | 0.120  | 0.189 |
| ØP  | 3.550       | 3.886  | 0.140  | 0.153 |
| Q   | 2.540       | 3.048  | 0.100  | 0.120 |

|   |                       |
|---|-----------------------|
| DOCUMENT NO.  | Z8B00003320           |
| SCALE   | 0<br>2.5<br>0 2.5 5mm |
| EUROPEAN PROJECTION   |                       |
|  |                       |
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